

Space charge for LIPAc IPMs

LIPAc: Linear IFMIF Prototype Accelerator

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J. Egberts's PhD thesis defended on September 25th, 2012 at Orsay (France) "IFMIF-LIPAc Beam diagnostics: Profiling and Loss Monitoring System" <u>http://irfu.cea.fr/Documentation/Theses/</u> Presently working in d-fine group (consulting)



Overview

- LIPAc: a quick overview
- IPM prototype

Electric field homogeneity:

- > Design
- tests at GSI
- Space Charge
 - Technique proposed for LIPAc:
 - SC algorithm
 - tests of the algorithm at CEA Saclay
- Summary



Accelerator: LIPAc Linear IFMIF Prototype Accelerator



Rokkasho (Japan) Deuteron beam \rightarrow 9 MeV \rightarrow I=125 mA cw \rightarrow 1.125 MW \rightarrow RF = 175 MHz (5.7 ns)

Present status of the commissioning

Proton & Deuteron injector commissioning: done RFQ commissioning: starting in May 2016

 \rightarrow IPM X&Y will be used in semester 2016 (5 MeV)



RFQ commissioning









SC processing for LIPAc

Hypothesis

- ionization by-products submitted to 2 electric field contributions
 - 1. IPM electric field applied on the IPM cage
 - 2. Space charge Electric field due to the beam contribution

Correction process

- transversal beam shapes describe by Generalized Gaussian distribution
- particle tracking in a realistic electric field IPM cage → generating profile distortions
- → Effect of distortions are determined and original profile can thus be reconstructed.

➔ roadmap of the presentation

- electric field uniformity
- SC correction



Electric field uniformity



IPM

"Small" prototype (aperture: 61 × 59 mm² - depth 40 mm)

- 32 strips for charge collection (pitch = 1.25 mm \rightarrow 40 mm active width)
- electric field uniformity → Electric field simulation by FEM (SOLMAXP)
- lateral degraders (150 $\mbox{M}\Omega\mbox{)}$ + 1 spire on top and bottom to reinforce the E-field homogeneity
- movable slits in longitudinal direction for monitoring the active length of strips
- typical applied voltage \sim 5 kV \Rightarrow E = 833 V/cm





Electric field: FEM simulation

Finite Element Method

• SOLMAXP (R. Duperrier, CEA Saclay, Irfu/SACM)

E_x component (V/m) in the transverse plane of the IPM

- no spire \rightarrow inhomogeneity < 30%
- spire (copper loop) → inhomogeneity < 3%



inhomogeneity < 30%

J. Egberts – April 2010

inhomogeneity < 3%



GSI test

Tests on the UNILAC of GSI (X2 branch devoted to GSI diagnostic team)

- \rightarrow May and November 2010
- \rightarrow examples of beam conditions:
 - 33 μA $^{48}\text{Ca}^{10\text{+}}$ at 4.6 MeV/A @ 5ms/s
 - 1.6 mA $^{238}\text{U}^{28+}$ at 4.8 MeV/A @ 100 $\mu\text{s/s}$
- → Residual gas: adjustable pressure from 5 10^{-7} mbar to 5 10^{-5} mbar









Electric field uniformity (1)

Beam conditions are kept frozen

- Stepper motor → accurate transversal displacement of the IPM
- IPM \rightarrow calculation of the central position of the beam







Electric field uniformity (2)

Aperture variation of the sliding window

- strip current rises linearly
- weak σ enlargement
 - \Rightarrow due to field inhomogeneity or to tilted strips?





Conclusion: E field uniformity seems to be quite good on "inner" transverse plane



Profile width: electrons/ions

Accelerating Field

Profile width

- electron profile much broader than ion profile
- profile width decrease with higher voltages





Space Charge



Space Charge effect \rightarrow LIPAc

Ionization products experienced

- IPM electric field
- Beam electric field: Space Charge
 - \rightarrow GSI: low I \Rightarrow negligible effect
 - \rightarrow IPHI: high I, low E \Rightarrow big effect (profile distortion)



How to counteract SC

- magnetic field for guidance → no space available
- increasing the electric field \rightarrow limitation due to deviation
- applying correction with an algorithm (developed by Jan Egberts)









Space Charge Algorithm (1)

1- Hypothesis

- D+
- round beam
- beam charge distribution described by a Generalized Gaussian Distribution (GGD) with no RF structure \rightarrow Maxwell Gauss equation to evaluate $\vec{E}(\mathbf{r})$
- 2- Approach
 - $\vec{P}_{corrected} = M \otimes \vec{P}_{measured}$
 - Matrix components M_{ij} represent the probability that an ion collected on strip j has been create at the position i
 - → beam distribution (GGD) & ions trajectories
 - Set of matrices computed for various parameter combinations

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I_{beam}: 1 to 125 mA → 35

\sigma: 5 to 15 mm → 21

\beta: -0.25 to 0.25 → 3

HV: 1

total matrices: 2205
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Note

the drift of the ions in the electric field is simulated for evaluating the probability components of the Matrix.

 $M_{k+2,i}$: probability that an ion emitted in k+2 cell is detected in i cell

Generalized Gaussian distribution

• μ: profile center





$$p_{\alpha,\beta,\mu}(x) = \frac{\beta}{2\alpha \Gamma(1/\beta)} e^{-\left[\frac{1}{\alpha}\right]}$$







Space Charge Algorithm (2)

- 3- First parameter to initiate iteration process
 - fit of the experimental profile using a GGD to extract

• iterations

$$\vec{P}_{1} = M(\sigma_{exp}, \beta_{exp}) \cdot \vec{P}_{Measured} \Longrightarrow \sigma_{1} \text{ and } \beta_{1} \text{ extraction from } \vec{P}_{1} \text{ fit}$$

$$\vec{P}_{2} = M(\sigma_{1}, \beta_{1}) \cdot \vec{P}_{1} \Longrightarrow \sigma_{2} \text{ and } \beta_{2} \text{ extraction from } \vec{P}_{2} \text{ fit}$$

$$\vec{P}_{n} = M(\sigma_{n-1}, \beta_{n-1}) \cdot \vec{P}_{n-1} \Longrightarrow \sigma_{n} \text{ and } \beta_{n} \text{ extraction from } \vec{P}_{n} \text{ fit}$$

until parameters converge ($\sigma_n \approx \sigma_{n-1}$; $\beta_n \approx \beta_{n-1}$) \rightarrow self consistent solution

- process is not a direct matrix product due to
 - \rightarrow experimental fit quality
 - \rightarrow σ and β are discrete quantities
 - \rightarrow 2 variables

but, iterating process is under control because the smaller σ_{final} the larger is σ_{exp} and anyway σ_{final} is always smaller than σ_{exp}



Algorithm test

Silhi source of Iphi (CEA Saclay)

- protons
- dc: few 10⁻³ up to cw
- E_{max} = 95 keV
- I_{max} = 100 mA
- P ~ 6 10⁻⁵ Torr

Silhi: Source of Light Ions at High Intensity Iphi: Injector of Protons at High Intensity

IPM was able to handle CW beam up to 21 mA.

Large aperture: $15 \times 15 \text{ cm}^2$ Degraders (16×2): 230 M Ω

→ Lorentz-3D for electric field uniformity FEE based on integrators; rate \approx 10 Hz HV_{max} = 16 kV









Algorithm test (2)

Tests done at Saclay on SILHI source: Dec. 2011 - Feb. 2012

proton E_{max} = 90 keV, I_{max} = 6 mA

Main test: SC algorithm

- frozen beam characteristics (conditions)
- only variation of extracting field











Good electric field uniformity was achieved for LIPAc IPMs

SC effect

an algorithm to correct SC was developed and tested with promising results

Nevertheless, mathematical algorithm like the one developed by Cyrille would be the solution firstly foreseen for ESS IPMs

Question: electrons or ions \rightarrow simulation to reproduce beam size?

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 SILHI – IPHI group at CEA Saclay

Thank your for your attention



Extra slides



LIPAc diagnostics



ACCT: AC Current Transformer BLoM: Beam Loss Monitor RGBLM: Residual Gas Bunch Length Monitor BPM: Beam Position Monitor DCCT: DC Current Transformer FC: Faraday Cup FFC: Fast Faraday Cup FCT: Fast Current Transformer IPM: Ionization Profile Monitor FPM: Fluorescence Profile Monitor μLoM: Micro Loss Monitor

Emittance meter

FC



Species fraction measurement

4 Profilers (CCD camera)



IFMIF

$I_{beam} = 2 \times 125 \text{ mA}$



Assumption:

- perfect electric field uniformity \rightarrow IPM with a large depth
- beam cross section: 25 × 100 mm²

\Rightarrow Space charge effect for IPM aperture:

- 200 mm (left)
- 300 mm (right)





SC for Asymmetric beam

 $\sigma_x = 6 \text{ mm} - \sigma_y = 9 \text{ mm}$

Search algorithm find profile with a $\sigma_x^{reconstructed}$ = 5.5 mm



Correction of an asymmetric Gaussian Beam, ox= 6 mm & oy= 9 mm



Profile comparison IPM / FPM

Extracted from « GSI SCIENTIFIC REPORT 2010 »

Characterization of a Non-Intensified Ionization Profile Monitor @ UNILAC

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At the same location (cross):

- IPM on 1 port
- FPM or BIF on a port at 90°

Note, walls were blackened to avoid reflection for CCD



FPM: Fluorescence Profile Monitor BIF: Beam Induced Fluorescence

Comparison of BIF and IPM Profiles in Different Gases

